

Notice of References Cited

Application/Control No.

10/072,357

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

2822

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,551,946 ✓	04-2003	Chen et al.	438/770
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	C	US-5,851,892 ✓	12-1998	Lojek et al.	438/305
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Li et al. "Gate Oxide Damage Reduction and Antenna Yield Improvement Using Low temperature Preclean for Sub-0.25 microns Metallization", June 1999, IEEE, pages 134-136.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.